

Form PTO-1449.

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1363SERIAL NO. 09/512,965
Filed HerewithLIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed HerewithGROUP 2858
Unknownjc525 US PTO
09/512,968

02/24/00

U.S. PATENT DOCUMENTS

| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
|-------------------|----|-----------------|--------|-------------------|-------|----------|----------------------------|
| | AA | 09/032,184 | | Akram et al. | | | 2/27/08 |
| VN | AB | 5,495,667 | 3/5/96 | Farnsworth et al. | 29 | 843 | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | Document Number | Date | Country | Class | Subclass | Translation | |
|--|----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| | AL | | | | | | | |
| | AM | | | | | | | |
| | AN | | | | | | | |
| | AO | | | | | | | |
| | AP | | | | | | | |

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|--|----|--|
| | AR | Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page |
| | AS | Good Things Come In Small BGA/CSP Packages from the Web Page of Johnstech International, Corporation, 1 page |
| | AT | Product Description for Test Socket Contacts from the Web Page of Johnstech International, Corporation, 1 page |

EXAMINER

and Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.

Form PTO-1449*

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1363SERIAL NO.
Filed HerewithLIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed HerewithGROUP
Unknown

U.S. PATENT DOCUMENTS

| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date if Appropriate |
|-------------------|----|-----------------|------|------|-------|----------|----------------------------|
| | AA | | | | | | |
| | AB | | | | | | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | Document Number | Date | Country | Class | Subclass | Translation | |
|--|----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| | AL | | | | | | | |
| | AM | | | | | | | |
| | AN | | | | | | | |
| | AO | | | | | | | |
| | AP | | | | | | | |

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|----|--|--|
| AR | | Product Description for Double Ended Probes, B1052 Series, from the Web Page of Rika Denshi America, Inc., 1 page |
| AS | | Product Description for Test Centers, RM 500 Series Probes, from the Web Page of Rika Denshi America, Inc., 1 page |
| AT | | Product Description for Cost Effective Interconnections for High I/O Products from the Web Page of Rika Denshi America, Inc., 1 page |

EXAMINER
*unk Nguyen*DATE CONSIDERED
01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed HerewithGROUP
Unknown 2858

U.S. PATENT DOCUMENTS

| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
|-------------------|----|-----------------|------|------|-------|----------|----------------------------|
| | AA | | | | | | |
| | AB | | | | | | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | Document Number | Date | Country | Class | Subclass | Translation | |
|--|----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| | AL | | | | | | | |
| | AM | | | | | | | |
| | AN | | | | | | | |
| | AO | | | | | | | |
| | AP | | | | | | | |

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

| | | |
|--|----|---|
| | AR | Product Description for Ball Grid Probe B1303-C3 from the Web Page of Rika Denshi America, Inc., 1 page |
| | AS | |
| | AT | |
| | | |

| | |
|--------------------------------|-------------------------------|
| EXAMINER <i>mark Nguyen</i> | DATE CONSIDERED 01/26/2001 |
|--------------------------------|-------------------------------|

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1363SERIAL NO.
09/512,968 09/512,968LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed HerewithGROUP 2858
2832

U.S. PATENT DOCUMENTS

| *Examiner Initial | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
|-------------------|-----------------|----------|----------|-------|----------|----------------------------|
| VN | AA 4,560,216 | 12/24/85 | Egawa | | | |
| VM | AB 4,754,555 | 7/5/88 | Stillman | | | |
| VV | AC 5,475,317 | 12/12/95 | Smith | | | |
| AD | | | | | | |
| AE | | | | | | |
| AF | | | | | | |
| AG | | | | | | |
| AH | | | | | | |
| AI | | | | | | |
| AJ | | | | | | |
| AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | Document Number | Date | Country | Class | Subclass | Translation | |
|----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | Yes | No |
| AL | | | | | | | |
| AM | | | | | | | |
| AN | | | | | | | |
| AO | | | | | | | |
| AP | | | | | | | |

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

| | |
|----|--|
| AR | Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page |
| AS | Good Things Come In Small BGA/CSP Packages from the Web Page of Johnstech International, Corporation, 1 page |
| AT | Product Description for Test Socket Connects from the Web Page of Johnstech International, Corporation, 1 page |
| | |

EXAMINER

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1363SERIAL NO.
09/512,968LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
February 24, 2000GROUP
Unknown 2858

U.S. PATENT DOCUMENTS

| *Examiner Initial | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
|-------------------|----|-----------------|---------|-----------|-------|----------|----------------------------|
| WN | AA | 5,325,052 | 6/28/94 | Yamashita | | | |
| | AB | | | | | | |
| | AC | | | | | | |
| | AD | | | | | | |
| | AE | | | | | | |
| | AF | | | | | | |
| | AG | | | | | | |
| | AH | | | | | | |
| | AI | | | | | | |
| | AJ | | | | | | |
| | AK | | | | | | |

FOREIGN PATENT DOCUMENTS

| | | Document Number | Date | Country | Class | Subclass | Translation | |
|--|----|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| | AL | | | | | | | |
| | AM | | | | | | | |
| | AN | | | | | | | |
| | AO | | | | | | | |
| | AP | | | | | | | |

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

| | | | |
|--|----|--|--|
| | AR | | |
| | AS | | |
| | AT | | |
| | | | |
| | | | |

RECEIVED

MAY 03 2000

TECHNOLOGY CENTER 2800

EXAMINER

Wanh Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.